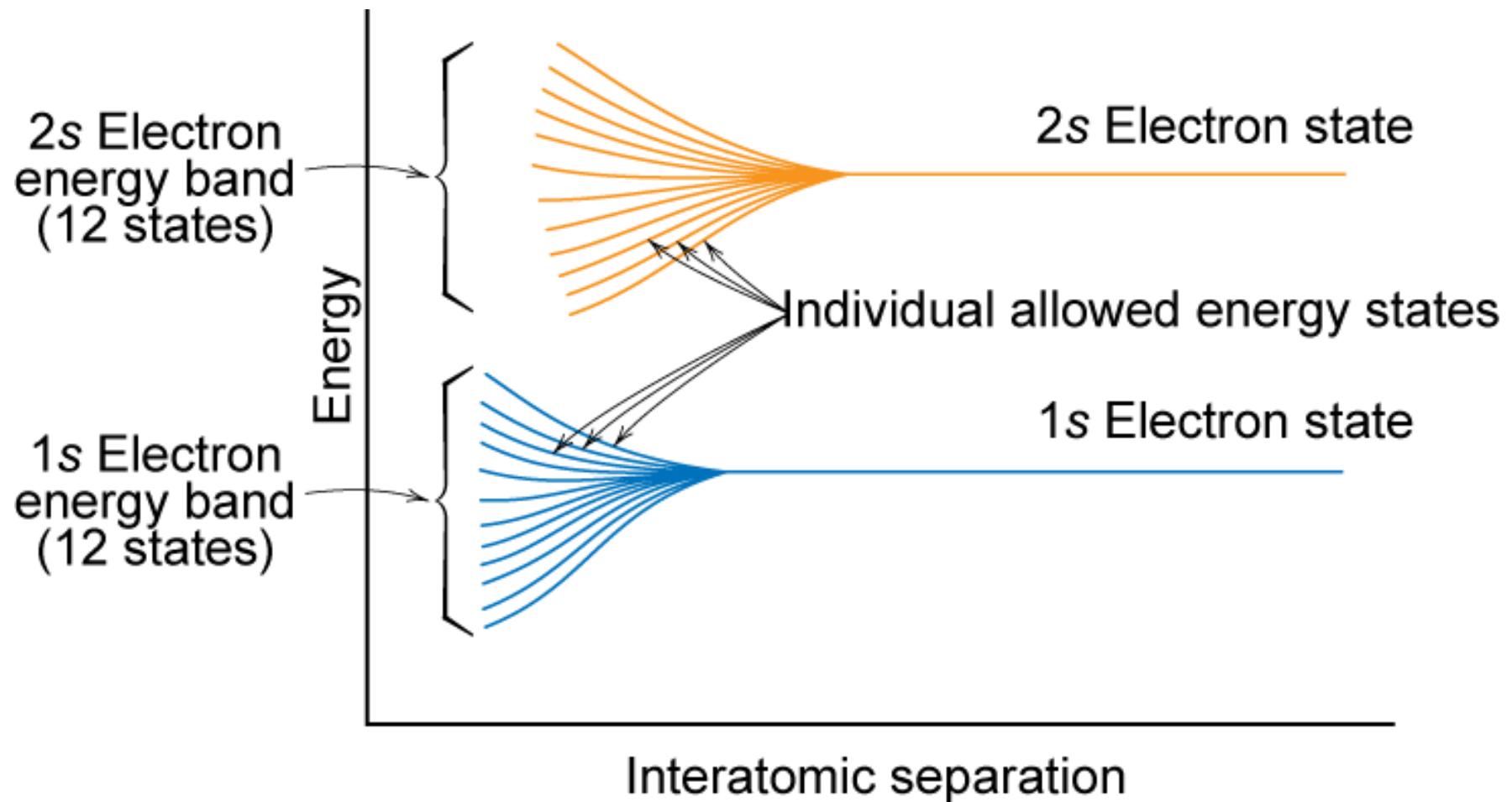


Chapter 18: Electrical Properties

- What are the physical phenomena that distinguish conductors, semiconductors, and insulators?
- For metals, how is conductivity affected by imperfections, T , and deformation?
- For semiconductors, how is conductivity affected by impurities (doping) and T ?

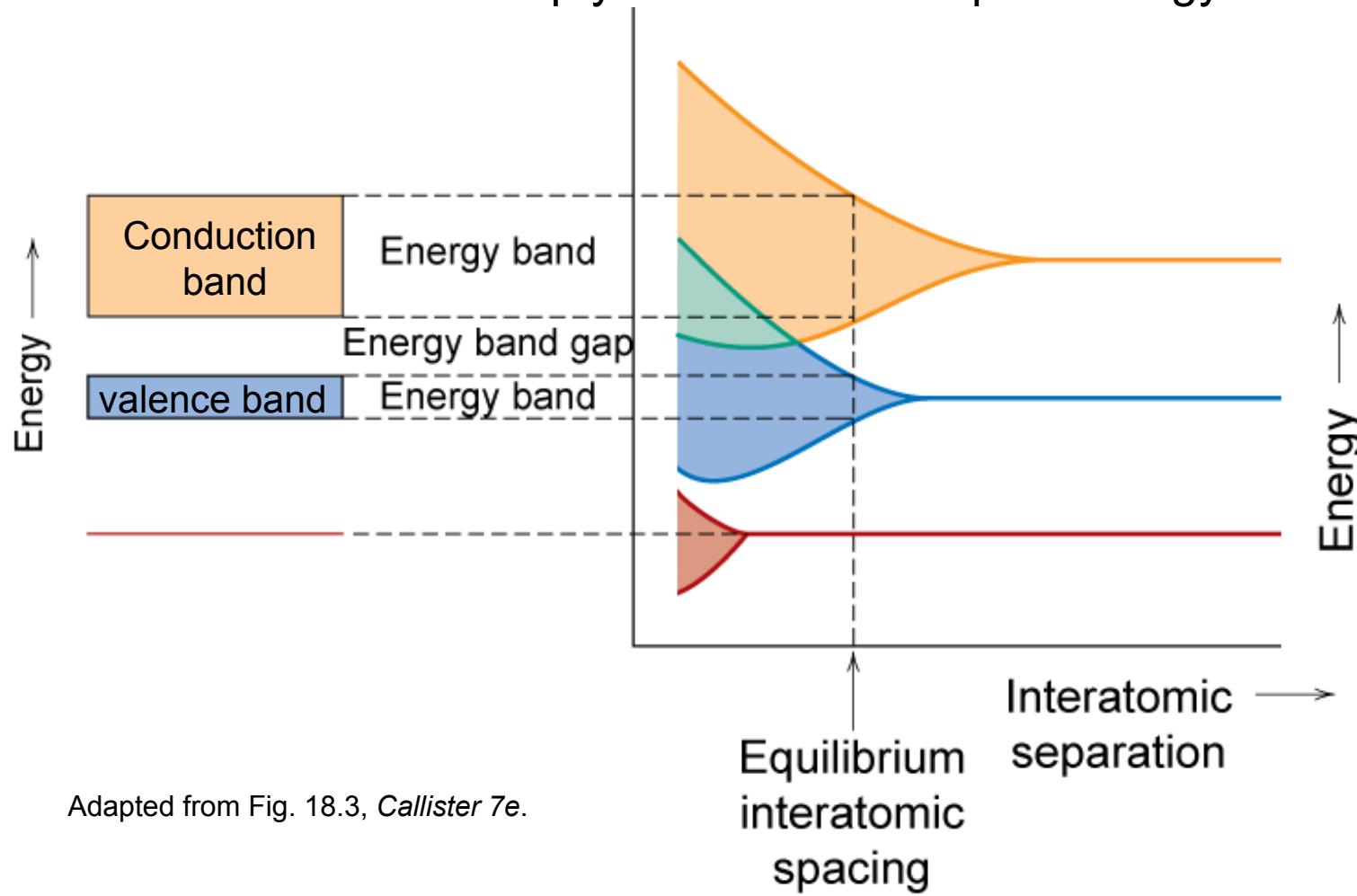
Electronic Band Structures



Adapted from Fig. 18.2, Callister 7e.

Band Structure

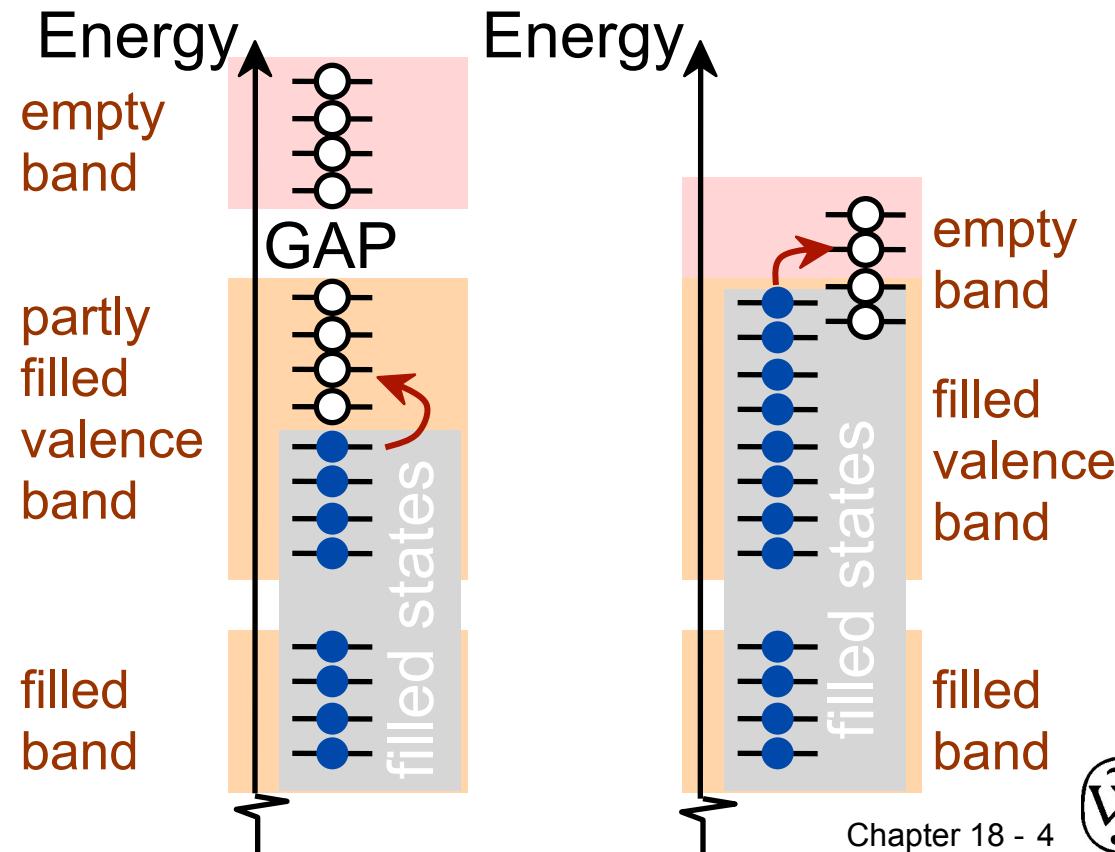
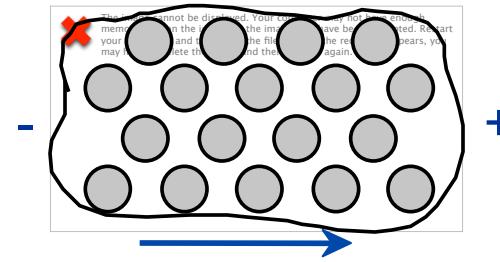
- Valence band – filled – highest occupied energy levels
- Conduction band – empty – lowest unoccupied energy levels



Adapted from Fig. 18.3, Callister 7e.

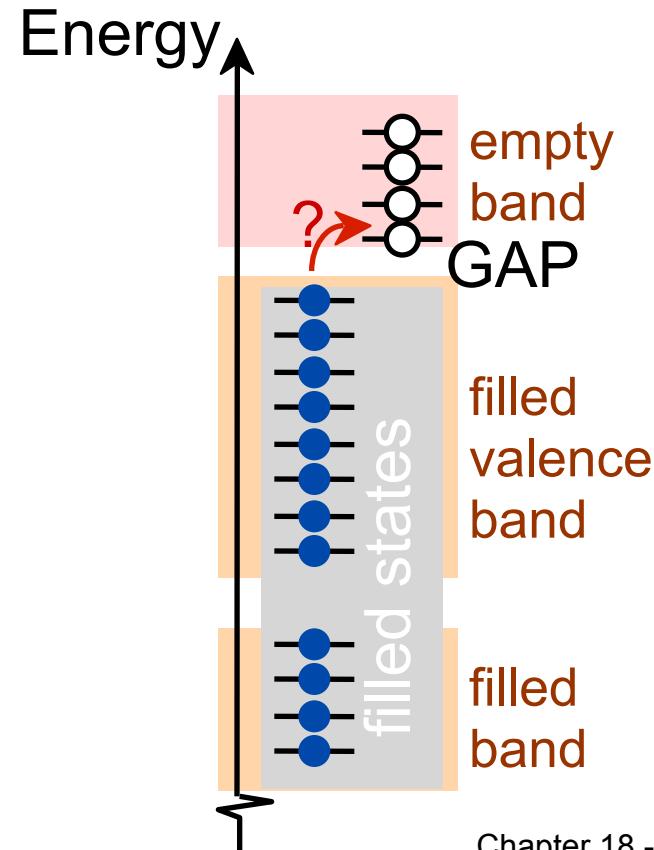
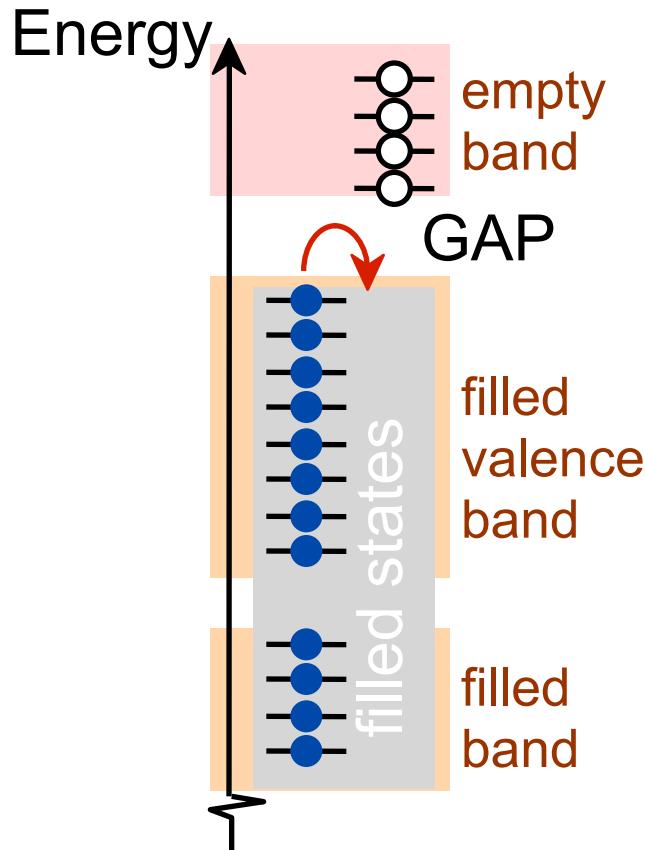
Conduction & Electron Transport

- Metals (**Conductors**):
 - Thermal energy puts many electrons into a higher energy state.
- Energy States:
 - for metals nearby energy states are accessible by thermal fluctuations.



Energy States: Insulators & Semiconductors

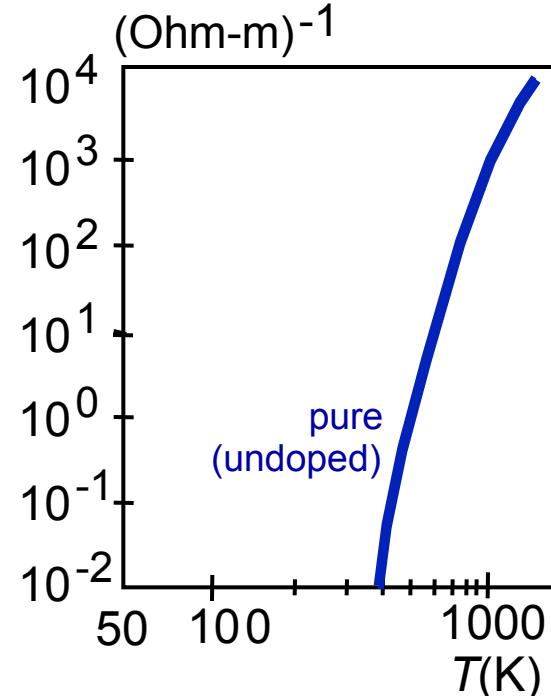
- Insulators:
 - Higher energy states not accessible due to gap (> 2 eV).
- Semiconductors:
 - Higher energy states separated by smaller gap (< 2 eV).



Pure Semiconductors: Conductivity vs T

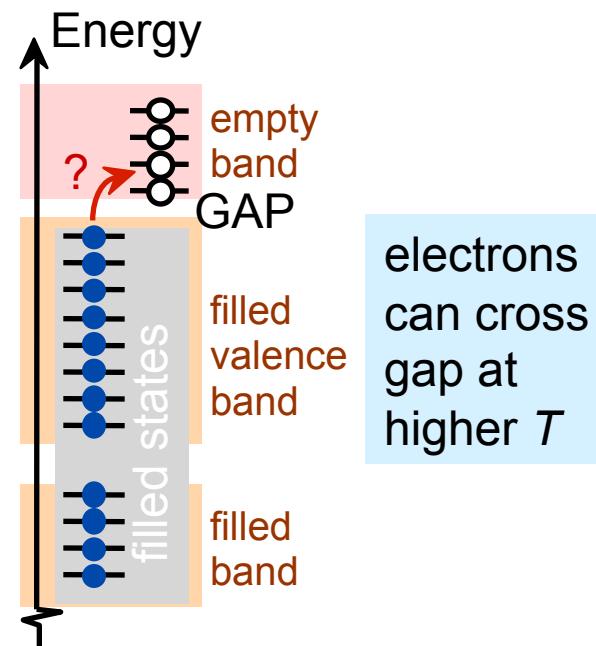
- Data for Pure Silicon:
 - σ increases with T
 - opposite to metals

electrical conductivity, σ



Adapted from Fig. 19.15, Callister 5e. (Fig. 19.15 adapted from G.L. Pearson and J. Bardeen, *Phys. Rev.* 75, p. 865, 1949.)

$$\sigma_{\text{undoped}} \propto e^{-E_{\text{gap}} / kT}$$



material	band gap (eV)
Si	1.11
Ge	0.67
GaP	2.25
CdS	2.40

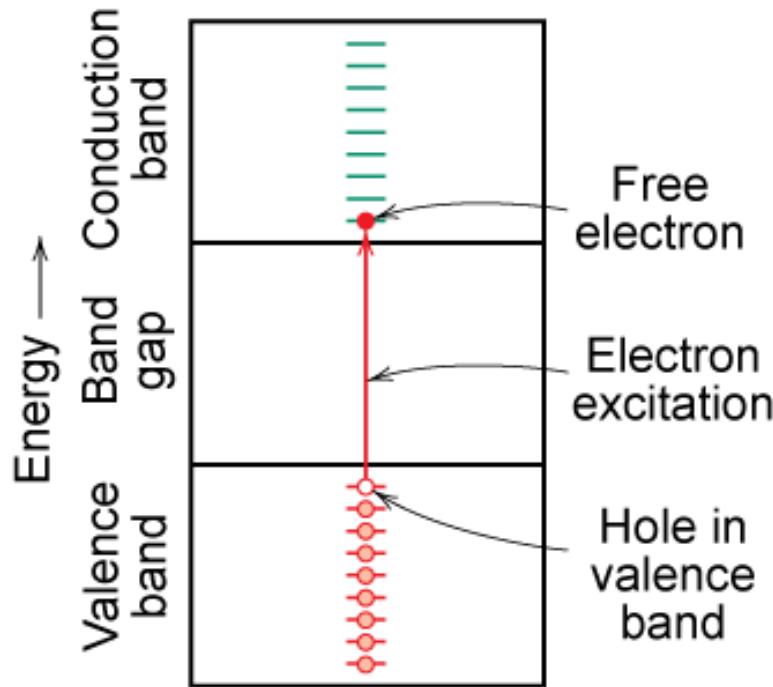
Selected values from Table 18.3, Callister 7e.

Chapter 18 - 6



Charge Carriers

Adapted from Fig. 18.6 (b), Callister 7e.



Two charge carrying mechanisms

Electron – negative charge

Hole – equal & opposite positive charge

Move at different speeds - **drift velocity**

Higher temp. promotes more electrons into the conduction band

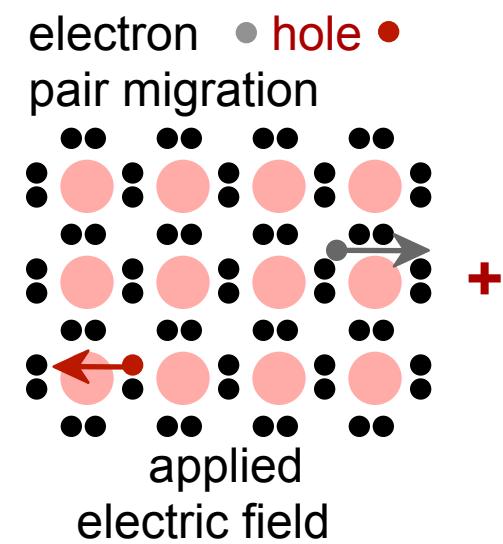
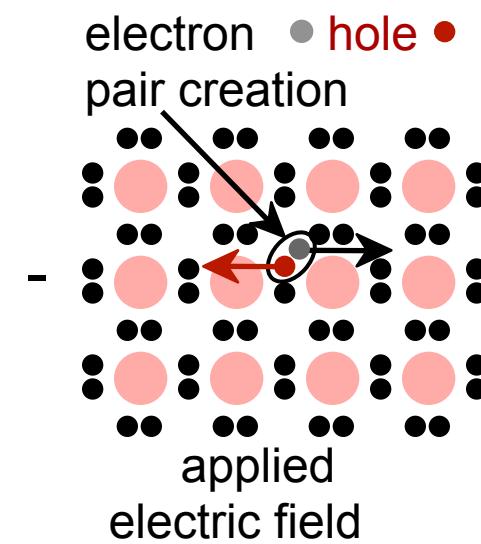
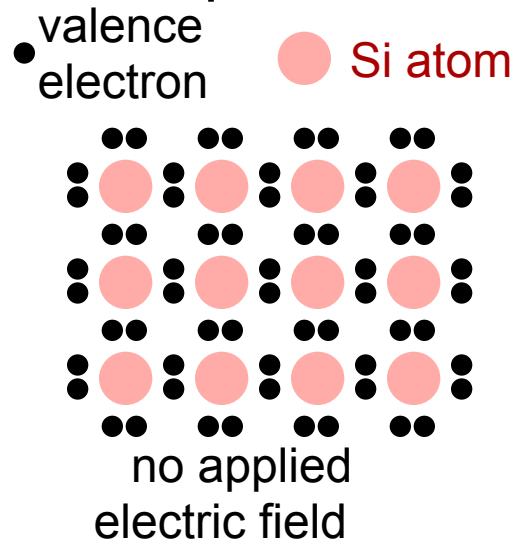
$\therefore \sigma \uparrow$ as $T \uparrow$

Electrons scattered by impurities, grain boundaries, etc.



Conduction in Terms of Electron and Hole Migration

- Concept of electrons and holes:



- Electrical Conductivity given by:

$$\sigma = n|e|\mu_e + p|e|\mu_h$$

electrons/m³

electron mobility

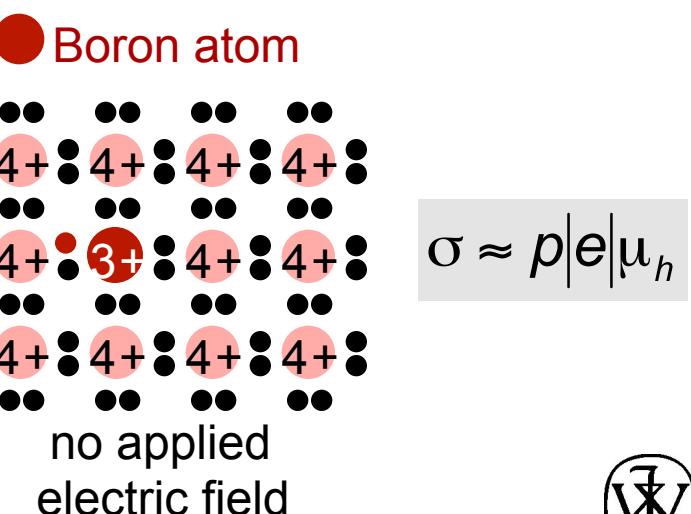
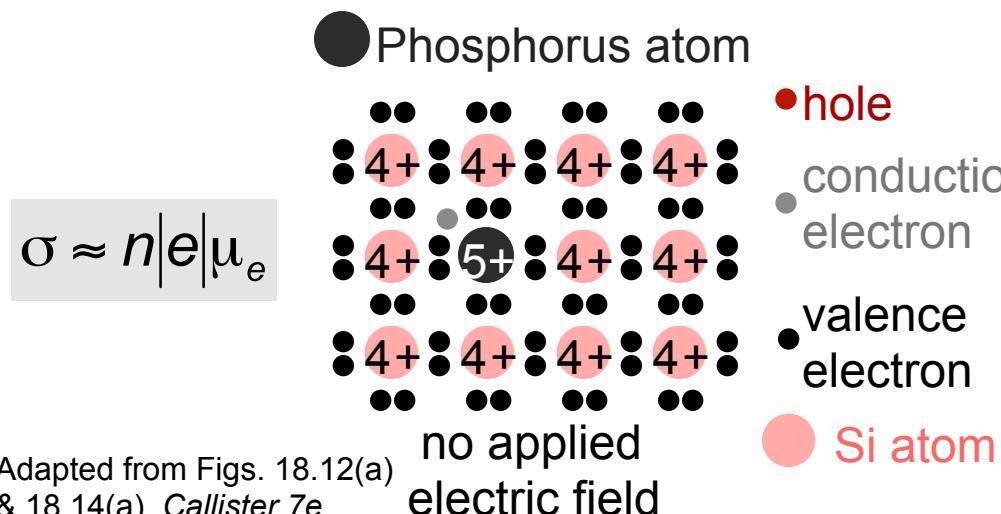
holes/m³

hole mobility

Adapted from Fig. 18.11,
Callister 7e.

Intrinsic vs Extrinsic Conduction

- **Intrinsic:**
 - # electrons = # holes ($n = p$)
 - case for pure Si
- **Extrinsic:**
 - $n \neq p$
 - occurs when impurities are added with a different # valence electrons than the host (e.g., Si atoms)
- ***n*-type Extrinsic: ($n \gg p$)**
- ***p*-type Extrinsic: ($p \gg n$)**



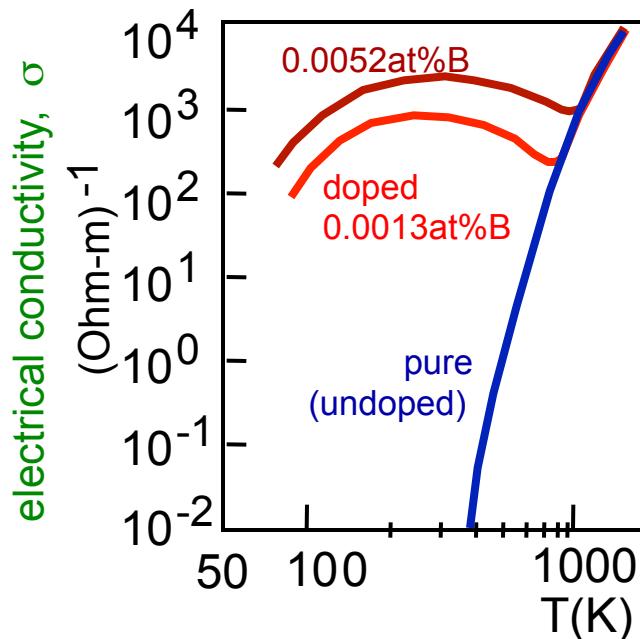
Adapted from Figs. 18.12(a) & 18.14(a), Callister 7e.

Intrinsic Semiconductors

- Pure material semiconductors: e.g., silicon & germanium
 - Group IVA materials
- Compound semiconductors
 - III-V compounds
 - Ex: GaAs & InSb
 - II-VI compounds
 - Ex: CdS & ZnTe
 - The wider the electronegativity difference between the elements the wider the energy gap.

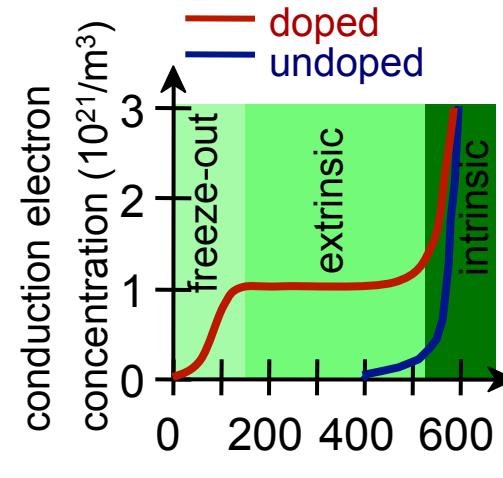
Doped Semiconductor: Conductivity vs. T

- Data for Doped Silicon:
 - σ increases doping
 - reason: imperfection sites lower the activation energy to produce mobile electrons.



Adapted from Fig. 19.15, Callister 5e. (Fig. 19.15 adapted from G.L. Pearson and J. Bardeen, *Phys. Rev.* **75**, p. 865, 1949.)

- Comparison: **intrinsic** vs **extrinsic** conduction...
 - extrinsic doping level: $10^{21}/m^3$ of a *n*-type donor impurity (such as P).
 - for $T < 100$ K: "freeze-out", thermal energy insufficient to excite electrons.
 - for 150 K $< T < 450$ K: "extrinsic"
 - for $T \gg 450$ K: "intrinsic"

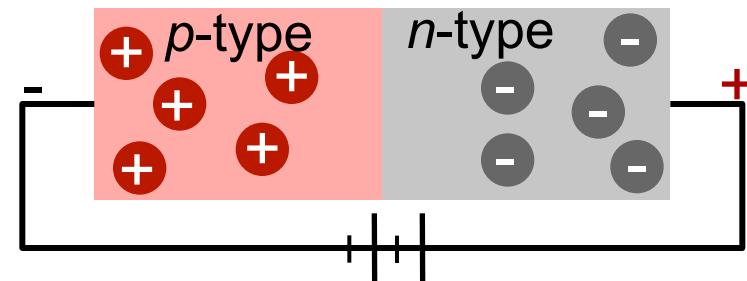
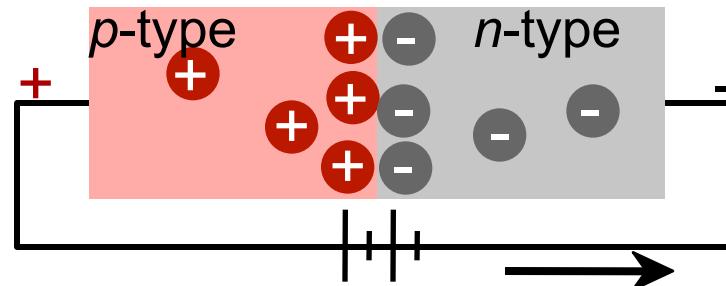
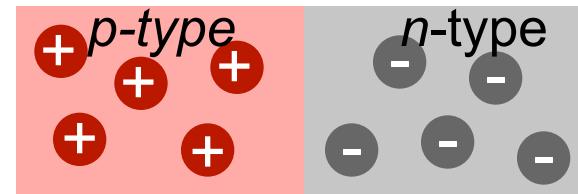


Adapted from Fig. 18.17, Callister 7e. (Fig. 18.17 from S.M. Sze, *Semiconductor Devices, Physics, and Technology*, Bell Telephone Laboratories, Inc., 1985.)

p-n Rectifying Junction

- Allows flow of electrons in one direction only (e.g., useful to convert alternating current to direct current).
- Processing: diffuse P into one side of a B-doped crystal.
- Results:
 - No applied potential:
no net current flow.
 - Forward bias: carrier flow through *p*-type and *n*-type regions; holes and electrons recombine at *p-n* junction; current flows.
 - Reverse bias: carrier flow away from *p-n* junction; carrier conc. greatly reduced at junction; little current flow.

Adapted from Fig. 18.21,
Callister 7e.



Properties of Rectifying Junction

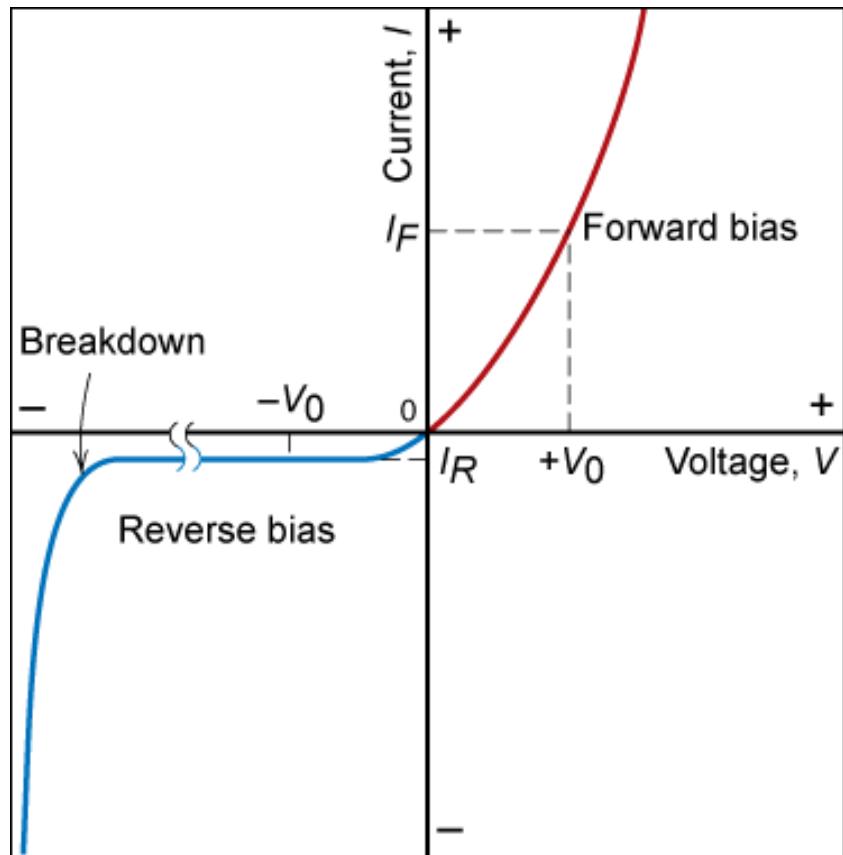


Fig. 18.22, Callister 7e.

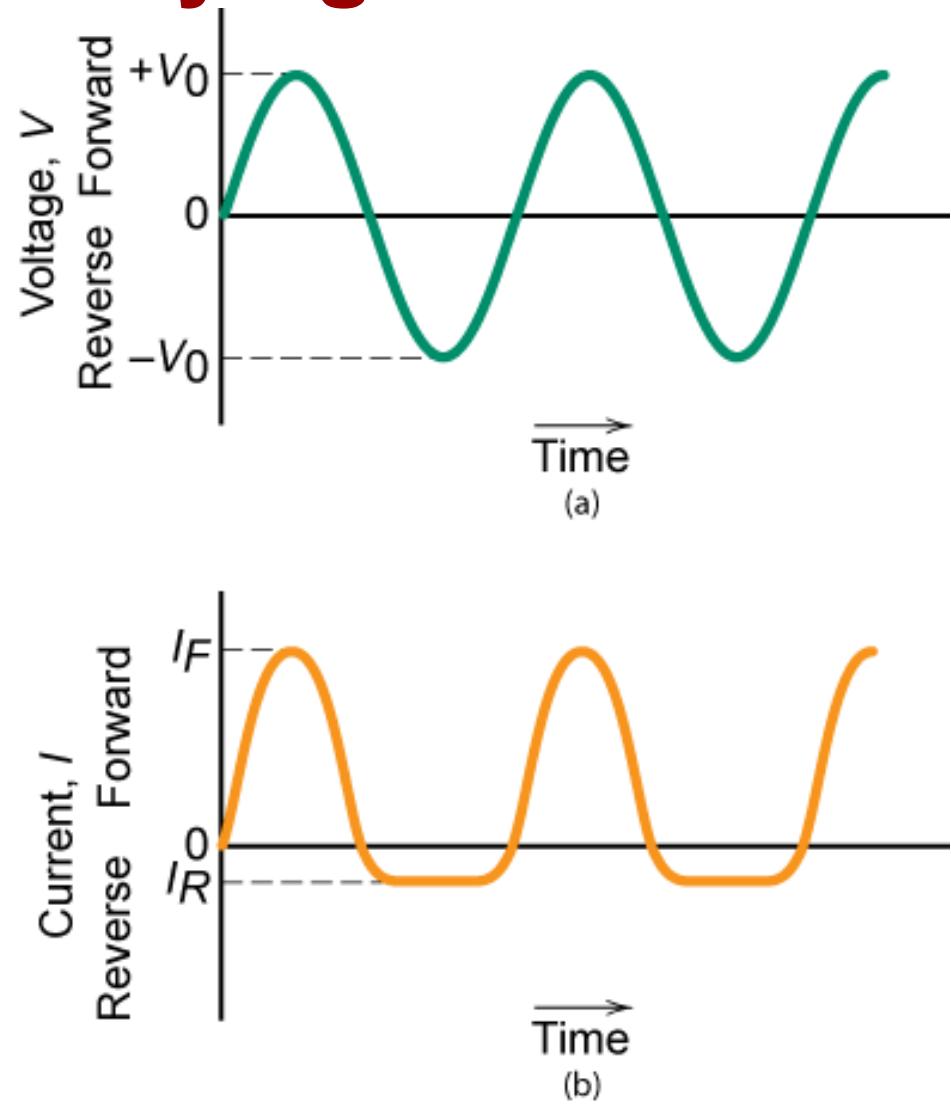


Fig. 18.23, Callister 7e.



Integrated Circuit Devices

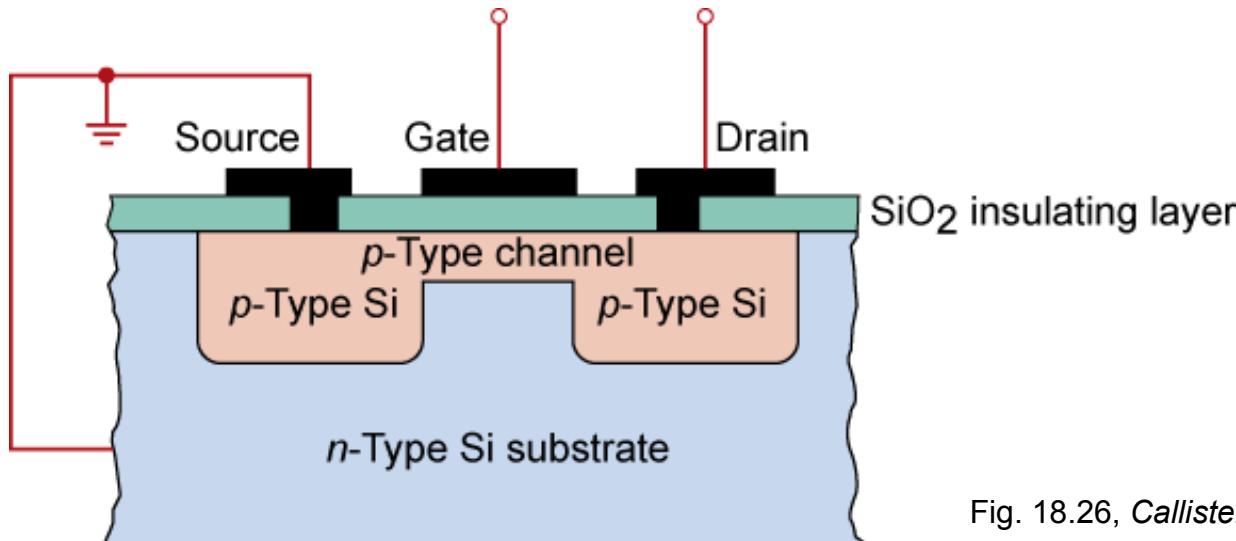


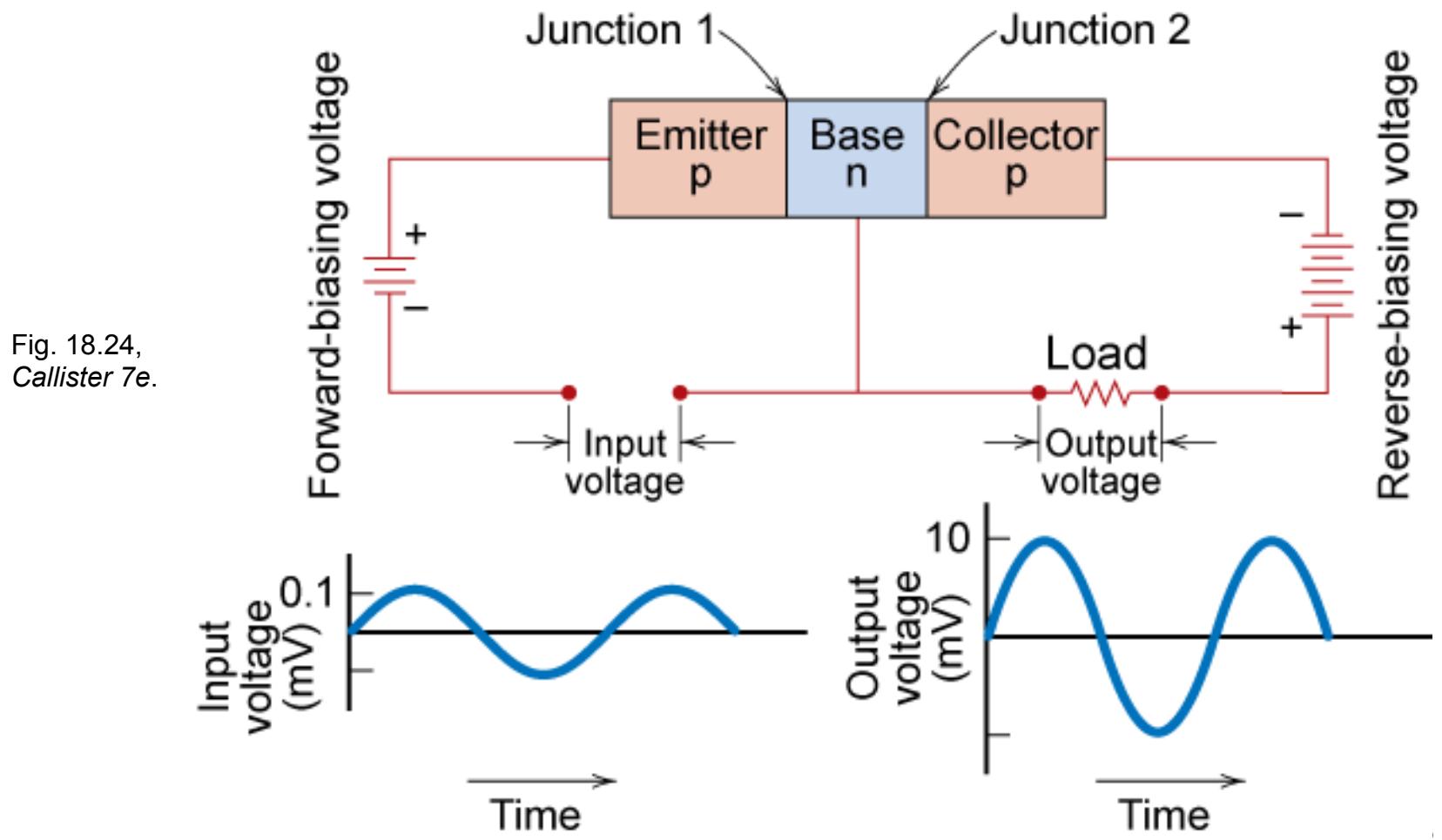
Fig. 18.26, Callister 6e.

- Integrated circuits - state of the art ca. 50 nm line width
 - 1 Mbyte cache on board
 - > 100,000,000 components on chip
 - chip formed layer by layer
 - Al is the “wire”

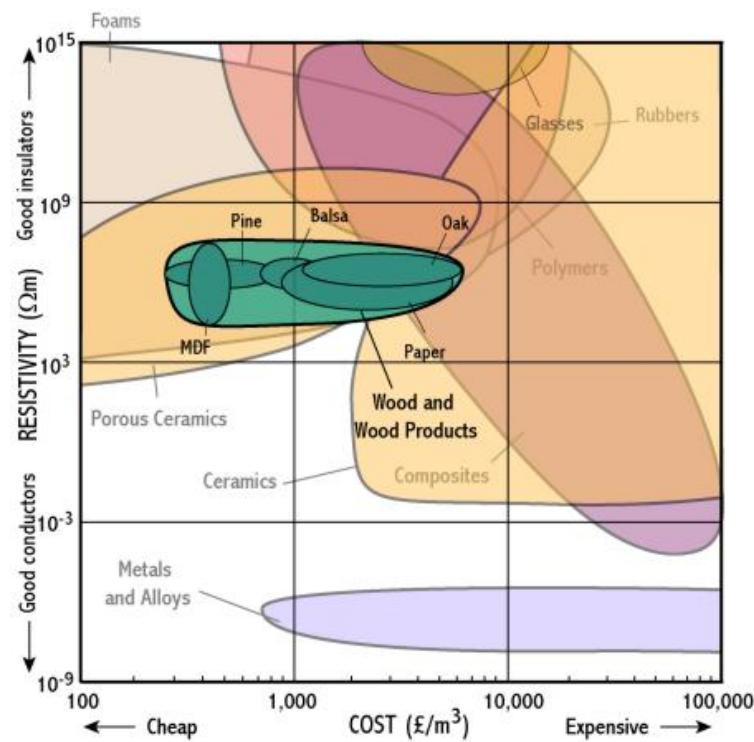


Transistor MOSFET

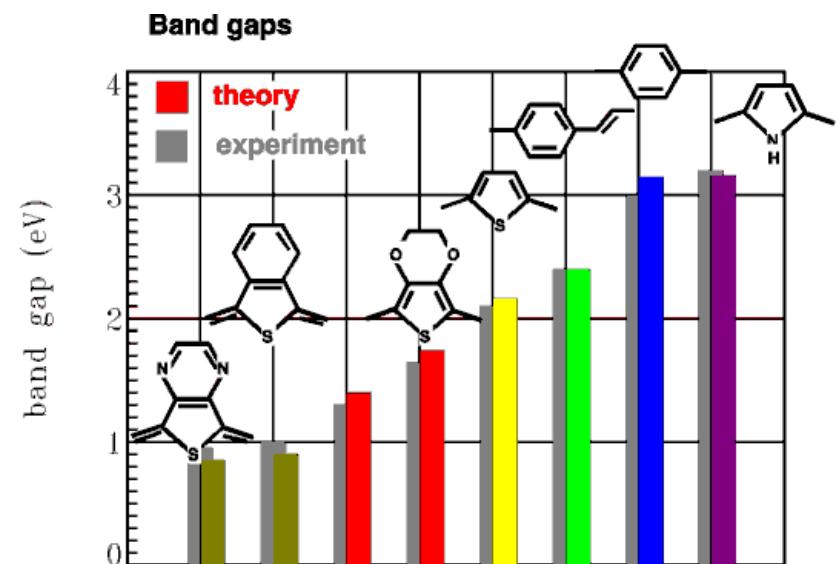
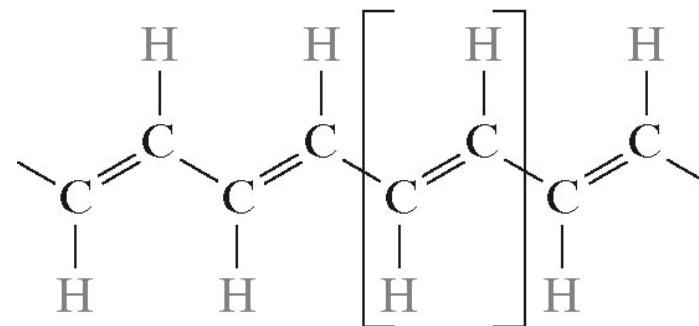
- MOSFET (metal oxide semiconductor field effect transistor)



Electrical Properties of Polymers

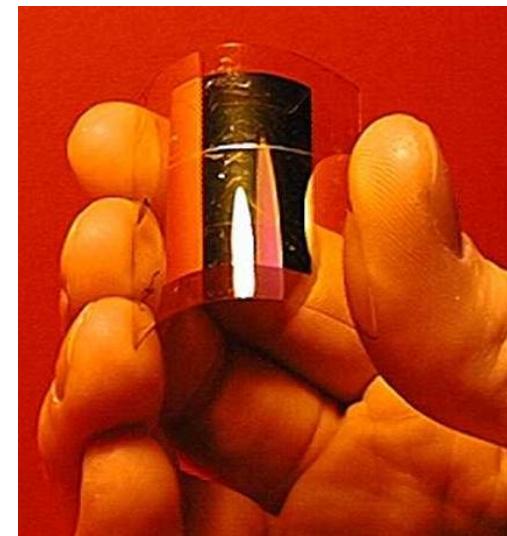
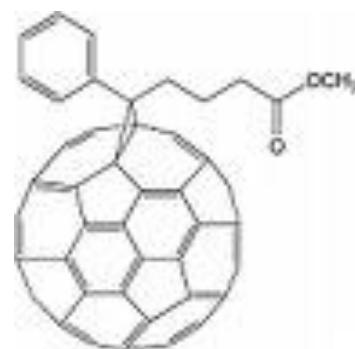
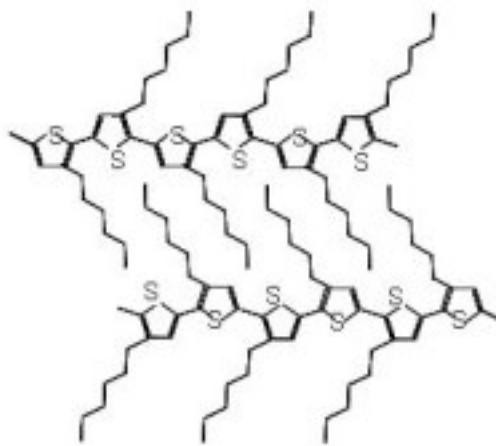
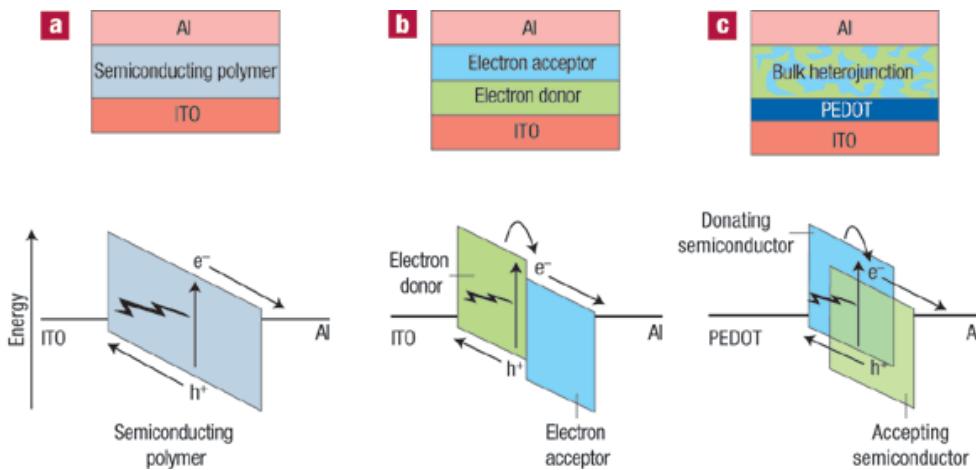


http://www-materials.eng.cam.ac.uk/mpsite/interactive_charts/resistivity-cost/NS6Chart.html



http://www.infochembio.ethz.ch/links/en/polymer_leitend.html Chapter 18 - 16

Polymer Solar Cells



ehf.uni-oldenburg.de

UNISOLAR® photovoltaic laminates

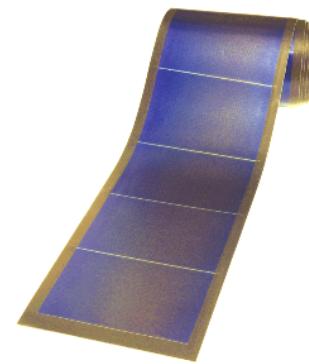


Photo courtesy of United Solar Ovonic, LLC

Nature Materials 5, 675 - 676 (2006)

Summary

- Electrical **conductivity** and **resistivity** are:
 - material parameters.
 - geometry independent.
- Electrical **resistance** is:
 - a geometry and material dependent parameter.
- Conductors, semiconductors, and insulators...
 - differ in accessibility of energy states for conductance electrons.
- For metals, conductivity is increased by
 - reducing deformation
 - reducing imperfections
 - decreasing temperature.
- For pure semiconductors, conductivity is increased by
 - increasing temperature
 - doping (e.g., adding B to Si (*p*-type) or P to Si (*n*-type)).

